FORM PTO 1449 (modified)  U.S. DEPARTMENT OF COMMERCE			ATTY DOCKET NO. APPLICATION NO. 10/769,765			65
LIST	U.S. DEPARTMENT OF COM PATENT AND TRADEMARK OF REFERENCES CITED BY (Use several sheets if nece:	APPLICANTO I P E	<i>X</i> .\	AOTO ET AL	••	
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*EXAMINER	DOCUMENT	R. C.	U SPATENT DOCUMENTS	<del></del>	<del>                                     </del>	FILING DATE
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inmo	2002-86461	11/2002	Korea			Abstract
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		OTHER DOCUMENT	(S) (Including Author, Title, Date, Pertinent Pages, Etc			
ymno	Lin et al., "Epitax Applied Physics		(Zr <sub>0.2</sub> Ti <sub>0.8</sub> ) O <sub>3</sub> on Si and its nanosc No. 14, April 2, 2001, pp. 2034-203		ctric prop	erties,"
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EXAMINER		45:06	DATE CONSIDERED 1.	-22-01	<del>/</del>	

Sheet 1 of 1

<sup>\*</sup>EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.